

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Jyh-Chun CHANG et. al.

Serial No: Unassigned

Filed: April 13, 2004

For: Integrated Type Probe Card And Its Fabrication Method

) Atty Dkt: CHAN3248/EM  
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Assistant Commissioner of Patents  
and Trademarks  
Alexandria, Virginia 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

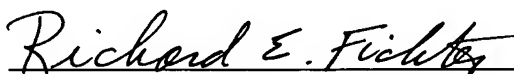
Sir:

Pursuant to Rule 37 C.F.R. §1.51(b), §1.56, §1.97, and §1.98, this Information Disclosure Statement is submitted in the above-identified patent application. A listing of documents to be published on the face of any patent granted from this application is submitted herewith on Form PTO-1449. Any other documents or information submitted for consideration by the Examiner are listed in this paper.

The Examiner is requested to acknowledge consideration of the information provided in this paper in accordance with prescribed procedures.

Please charge any additional fees or credit any overpayments in connection with this paper to Deposit Account No. 02-0200.

Respectfully submitted,



Richard E. Fichter  
Registration No. 26,382

Date: April 13, 2004

BACON & THOMAS, PLLC  
625 Slaters Lane, 4th Floor  
Alexandria, Virginia 22314  
Telephone: (703) 683-0500

<b>B/O Form PTO-1449</b>  U.S. Department of Commerce Patent and Trademark Office  Information Disclosure Statement by Applicant	<b>Atty. Docket Number</b> <b>CHAN3248/EM</b>	<b>Serial Number</b> <b>Unassigned</b>
	<b>Applicant</b> <b>Jyh-Chun CHANG et. al.</b>	
	<b>Filing Date</b> <b>Concurrently Herewith - April 13, 2004</b>	<b>Group</b> <b>Unassigned</b>

## U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
	4,027,935	06/07/1977	Byrnes et. al.			06/21/1976
	4,754,256	06/28/1988	Fluhr et. al.			11/28/1986
	5,090,118	02/25/1992	Kwon et. al.			07/31/1990
	5,475,318	12/12/1995	Marcus et. al.			10/29/1993
	6,072,190	06/06/2000	Watanabe et. al.			11/18/1996
	2002/0080588 A1	06/27/2002	Eldridge et. al.			12/27/2001

## Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No

## Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)


Examiner	Date Considered
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EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.